

SEMITRANS[®] 3

Trench IGBT Modules

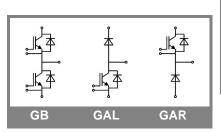
SKM 200GB123D SKM 200GAL123D SKM 200GAR123D

Features

- MOS input (voltage controlled)
- N channel, homogeneous Si
- Low inductance case
- Very low tail current with low temperature dependence
- High short circuit capability, self limiting to 6 x I_{cnom}
- Latch-up free
- Fast & soft inverse CAL diodes
- Isolated copper baseplate using DCB Direct Copper Bonding Technology
- Large clearance (13 mm) and creepage distances (20 mm)

Typical Applications

- AC inverter drives
- UPS



Absolu	te Maximum Ratings	$T_c = 2$	25 °C, unless otherwise	specified
Symbol Conditions			Values	Units
IGBT				
V _{CES}	T _j = 25 °C		1200	V
I _C	T _j = 150 °C	T _{case} = 25 °C	200	A
		T _{case} = 85 °C	180	A
I _{CRM}	I _{CRM} =2xI _{Cnom}		300	А
V_{GES}			± 20	V
t _{psc}	V_{CC} = 600 V; $V_{GE} \le 20$ V; VCES < 1200 V	T _j = 125 °C	10	μs
Inverse	Diode			
I _F	T _j = 150 °C	T _{case} = 25 °C	200	А
		T _{case} = 80 °C	130	A
I _{FRM}	I _{FRM} =2xI _{Fnom}		300	А
I _{FSM}	t _p = 10 ms; sin.	T _j = 150 °C	1440	А
Freewh	eeling Diode			
۱ _F	T _j = 150 °C	T _{case} = 25 °C	260	А
		T _{case} = 80 °C	180	Α
I _{FRM}	I _{FRM} =2xI _{Fnom}		400	А
I _{FSM}	t _p = 10 ms; sin.	T _j = 150 °C	1800	А
Module	1			
I _{t(RMS)}			500	А
T _{vj}			- 40 + 150 (125)	°C
T _{stg}			- 40+ 125	°C
V _{isol}	AC, 1 min.		2500	V

Characteristics		T _c =	$_{\rm c}$ = 25 °C, unless otherwise specified				
Symbol	Conditions		min.	typ.	max.	Units	
IGBT							
V _{GE(th)}	$V_{GE} = V_{CE}, I_{C} = 6 \text{ mA}$		4,5	5,5	6,5	V	
I _{CES}	V_{GE} = 0 V, V_{CE} = V_{CES}	T _j = 25 °C		0,1	0,3	mA	
V _{CE0}		T _j = 25 °C		1,4	1,6	V	
		T _j = 125 °C		1,6	1,8	V	
r _{CE}	V _{GE} = 15 V	T _j = 25°C		7,33	9,33	mΩ	
		$T_{j} = 125^{\circ}C$		10	12,66	mΩ	
V _{CE(sat)}	I _{Cnom} = 150 A, V _{GE} = 15 V	T _j = °C _{chiplev.}		2,5	3	V	
C _{ies}				10	13	nF	
C _{oes}	V_{CE} = 25, V_{GE} = 0 V	f = 1 MHz		1,5	2	nF	
C _{res}				0,8	1,2	nF	
Q _G	V _{GE} = -8V - +20V			1500		nC	
R _{Gint}	T _j = °C			2,5		Ω	
t _{d(on)}				220	400	ns	
t, E _{on}	R _{Gon} = 5,6 Ω	V _{CC} = 600V		100	200	ns	
Eon		I _{Cnom} = 150A		24		mJ	
t _{d(off)}	R _{Goff} = 5,6 Ω	T _j = 125 °C		600	800	ns	
t _f		V _{GE} = -15V		70	100	ns	
E _{off}				17		mJ	
R _{th(j-c)}	per IGBT				0,09	K/W	

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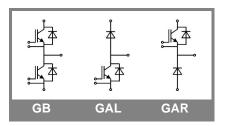
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Characte				4		L Luite
•	Conditions		min.	typ.	max.	Units
		T - 05 °C		0	0.5	
$v_F = v_{EC}$	I _{Fnom} = 150 A; V _{GE} = 0 V			2	2,5	V V
N/		$T_j = 125 \ ^\circ C_{chiplev.}$ $T_j = 25 \ ^\circ C$		1,8	4.0	-
V _{F0}		$T_j = 25 {}^{\circ}C$		1,1	1,2	V
		T _j = 125 °C		0	0.7	V
r _F		$T_j = 25 \degree C$		6	8,7	mΩ
		$T_j = 125 \ ^{\circ}C$ $T_j = 125 \ ^{\circ}C$				mΩ
I _{RRM}	I _{Fnom} = 150 A di/dt = 1500 A/μs	Т _ј = 125 °С		90		A
Q _{rr}				8		μC
E _{rr}	V _{GE} = -15 V; V _{cc} = 600V			6,6		mJ
R _{th(j-c)D}	per diode				0,25	K/W
	eling Diode					
$V_F = V_{EC}$	I_{Fnom} = 200 A; V_{GE} = 0 V			2	2,5	V
		$T_j = 125 \ ^\circ C_{chiplev.}$ $T_j = 25 \ ^\circ C$		1,8		V
V _{F0}		T _j = 25 °C		1,1	1,2	V
		T _j = 125 °C				V
r _F		T _j = 25 °C		4,5	6,5	V
		T _j = 125 °C				V
IRRM	I _{Fnom} = 200 A	T _j = 125 °C		120		Α
Q _{rr}	di/dt = 2000 A/µs	-		11		μC
Err	V_{GE} = 0 V; V_{CC} = 600 V					mJ
R _{th(j-c)FD}	per diode				0,18	K/W
Module						
L _{CE}				15	20	nH
R _{CC'+EE'}	res., terminal-chip	T _{case} = 25 °C		0,35		mΩ
00 FLL		T _{case} = 125 °C		0,5		mΩ
R _{th(c-s)}	per module				0,038	K/W
M _s	to heat sink M6		3		5	Nm
M _t	to terminals M6, M4		2,5		5	Nm
W					325	g

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

This technical information specifies semiconductor devices but promises no characteristics. No warranty or guarantee expressed or implied is made regarding delivery, performance or suitability.





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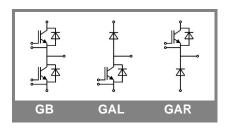
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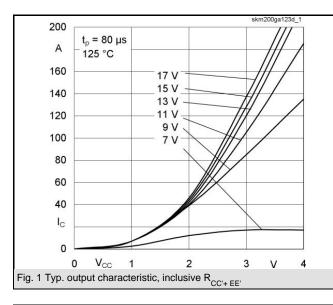
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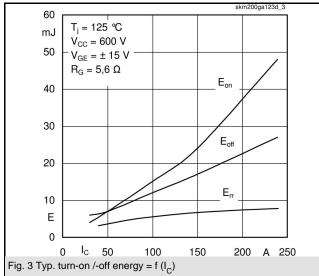
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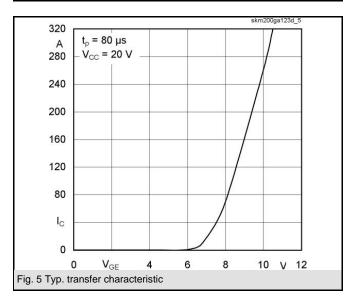


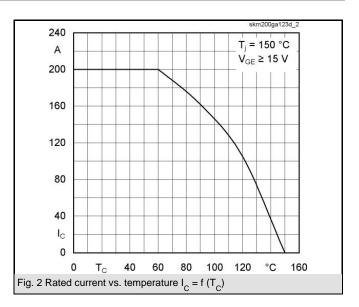
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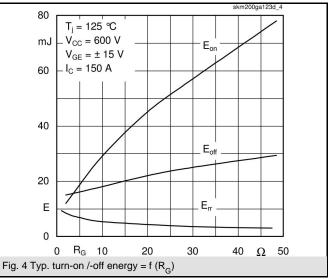
Z _{th}			
Symbol	Conditions	Values	Units
Z R _i			
R _i	i = 1	59	mk/W
R _i	i = 2	23	mk/W
R _i	i = 3	6,8	mk/W
R _i	i = 4	1,2	mk/W
tau	i = 1	0,03	s
tau _i	i = 2	0,0087	s
tau _i	i = 3	0,002	s
tau _i	i = 4	0,0002	s
Z R _i th(j-c)D	·		•
R _i	i = 1	170	mk/W
R _i	i = 2	66	mk/W
R _i	i = 3	12	mk/W
R _i	i = 4	2	mk/W
tau _i	i = 1	0,0348	s
tau	i = 2	0,0072	s
taui	i = 3	0,077	s
tau _i	i = 4	0,0002	S

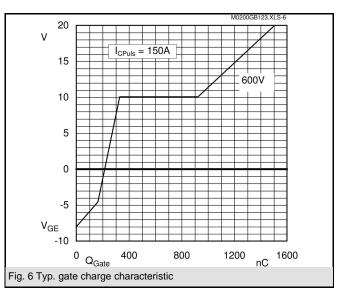




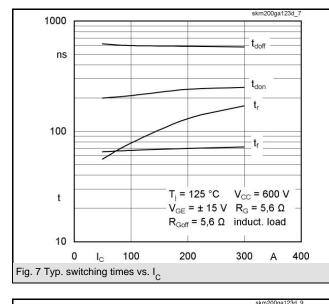


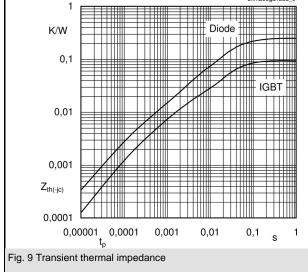


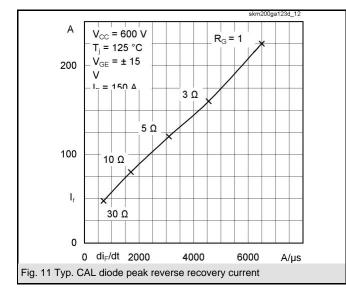


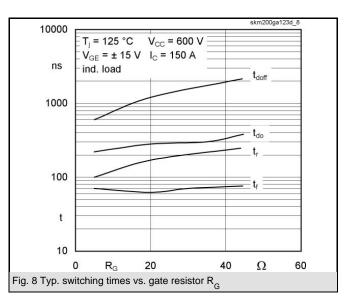


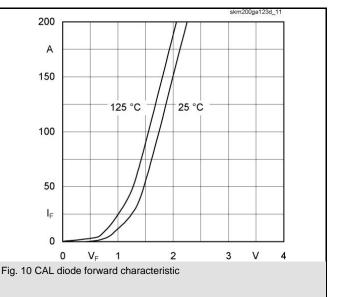
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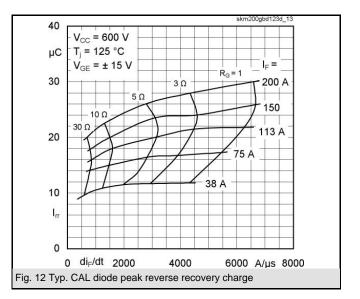




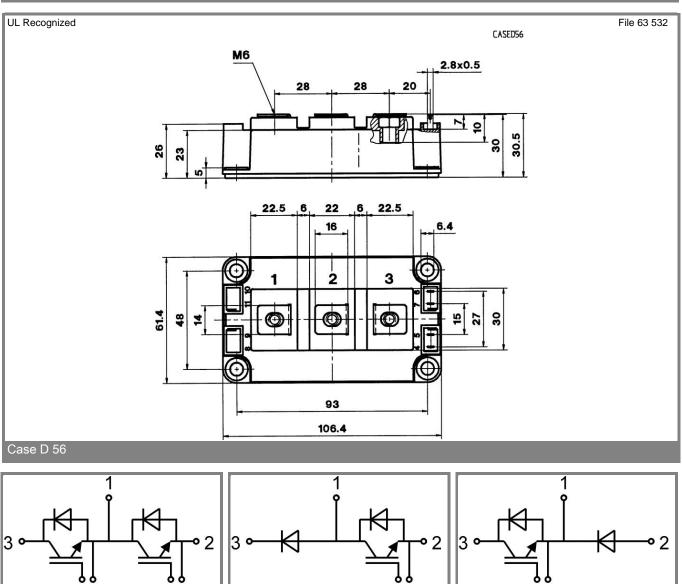








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6 7

GAL

4 5

Case D 58 (→

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GAR

45

Case D 56

6 7

GB

Case D 57 (→

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